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Advances in Ultra-Wide Bandgap Devices

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Deadline for manuscript submissions:

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Message from the Guest Editor

This Special Issue aims to highlight recent developments and the state of the art in the field of UWBG and devices, including both experimental results and theoretical developments. These include advances in all important aspects of key materials such as Ga₂O₃, AlN, BN, AlGaN, and diamond; as well as the modelling, simulation, design, epitaxy, fabrication technology, reliability, novel device architectures, advanced characterizations and applications to improve the performance of devices and circuits.

This Special Issue will report on new advancements in Ultra-Wide bandgap devices that include, but are not limited to, the following topics:

- UWBG growth and material properties
- power electronics
- device simulation
- processing
- electrical and structural characterization.











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Message from the Editor-in-Chief

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